



MQXF quench protection

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with inputs from

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6th HL-LHC Collaboration Meeting

15 November 2016





• Summary of the MQXF quench protection report

- Circuit analysis
- Quench heater configuration
- CLIQ configuration
- Effect of strand parameters
- Worst-case analysis
- MQXFS01 and MQXFS03 quench protection tests
 - Quench heater delays
 - Quench integral studies
 - CLIQ performance
- Conclusions & next steps

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		REPORT			
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Abstract					
This docum circuit. The sensitivity a	ent describes the restudies include a con nalyses to conducto	sults of the quench protection studies mparison between the performance o r parameters, and failure scenarios.	for the High-Lumi f different protect	inosity LHC i tion system	inner triplet configuration
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Simulated currents in the circuit





Simulated voltages to ground





Voltages to ground and between coil sections in Q1/Q3 are 40% lower than Q2a/Q2b

QH connection scheme





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Options for the quench protection

















with LEDET

Simulated voltages to ground











Effect of QH strip failures – Hot-spot T





Effect of QH strip failures – U to ground





Revision of the worst-case peak Uground



Guidelines followed to define the reference worst-case peak voltages to ground

- Values at <u>nominal current</u> (not at ultimate current) are chosen
- Worst-case failure includes <u>2 QH circuit failing simultaneously</u>
- Influence of <u>strand parameters</u> studied, but corrective measures can be taken to avoid reaching the worst conditions. Hence, the reference values <u>will not</u> <u>consider</u> the influence of strand parameters.

Following these guidelines, the voltage to ground reference values are:

- 0-QH: 868 V
- O-QH+I-QH: 928 V
- 0-QH+CLIQ: 667 V

The previous reference value was 520 V, calculated in the case of O-QH+CLIQ. The increase with respect to this value comes from the improvement in the <u>model</u> <u>accuracy</u> and from the detailed analysis of the effect of the <u>initial hot-spot position</u>.

However, it is recommended that no correction of the test values during electrical quality be asked, considering that prudent safety margins were applied $(2xU_{ground,peak} + 500 \text{ V}).$





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Cpr with simulated 7m MQXF baseline





Quench integral studies – MQXFS1b





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Quench protection report prepared

- Extensive simulation work aimed at identifying
 - Performances of various quench protection options
 - Effect of strand parameters and quench location
 - Effect of QH failures
 - Peak currents in all circuit elements
- Option with only O-QH does not offer enough protection, either I-QH or CLIQ (or both) are needed as well. Combination of protection elements guarantees great redundancy.

Test results

- Quench protection up to nominal current successfully demonstrated
- CLIQ tested for the first time on an MQXF model. As expected, a significant reduction of the quench load is achieved with respect to O-QH only. Direct comparison with O-QH+I-QH not available from experimental results yet.
- Quench protection at low current assured by O-QH, baseline parameters ok

Next steps

- Test response time of inner-layer quench heaters at nominal current on MQXFS3
- Test CLIQ performance on MQXFS3
- Quench integral studies at nominal/ultimate current
- Compare test results with simulations with the same RRR and QH conditions









6 CLIQ units and 4 warm diode strings per triplet

AC currents



Parallel diodes only carry small current differences between magnets during the discharge



Voltages to ground just after triggering

CLIQ-induced voltage distribution



 The voltage distribution in the windings just after triggering CLIQ remains almost constant along the magnet length, but is inhomogeneous in the magnet cross-section



QH-induced voltage distribution



The voltage distribution in the QH strips just after triggering varies linearly along the conductor length, but is homogeneous in the cross-section

Coil to heater voltage optimization



• CLIQ and QH are triggered simultaneously. It is important to choose a QH connection scheme that compensates the voltages induced by CLIQ and QH





Simulated temperature profiles













Minimum QH energy density to quench

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Measured and simulated heater delays *LARP* – Outer layer



Measured and simulated heater delays – Inner layer

200



MQXFS01 stainless-steel only IL heaters not yet tested



Measured and simulated heater delays – Outer and inner layers





Energy extraction decays (no heaters) LARP





Energy extraction decays (no heaters) Quench back and inductance reduction

l₀=8.24 kA R_{FF}=90 mΩ

 L_{diff} ~50% L_{nom} R_{coil} ~5 m Ω \rightarrow The faster decay observed in this discharge is mainly due to a reduction of the inductance, not due to quench-back



Fast kick due to quench heater firing

- Delay of ~3 ms (33 turns) observed (training & beam induced quenches, MD) between quench heater firing and beam dump in LHC main dipoles.
- Field from quench heater rises within 20 30 us.
- Max expected orbit excursions:
 - Main dipoles , 11 T dipole: ~ 0.13 σ
 - HL-LHC triplet (OL + IL): ~ 0.5 σ → ~150 um (@ 7 TeV); ~ 6 mm (@ 450 GeV)
- Minimize skew dipole fields from quench heaters.
- Ensure, that beams are dumped before quench heater fire.

